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1/PTO U.S. Department of	Commerce					
Rev. 10/95 Patent and Trade		Application Number	10/782,267			
		Filing Date	February	18, 200	14	
TRANSMITTAL FOR	M	First Named Inventor	Steven W.	Meeks	s	
(to be used for all correspondence during pe filed application)	endency of	Group Art Unit Number	2877			•
		Examiner Name .	Not Yet K	nown		
Total Number of Pages in This Submission	8*	Attorney Docket Number	20830-088	55		
ENCL	OSURES	(check all that apply	/) .			
Fee Transmittal Form (in duplicate) Check Enclosed Return Receipt Postcard Response to Notice to File Missing Parl Assignment & Recordation Cover Sheel Declaration Power of Attorney Application Data Sheet Information Disclosure Statement & PT Copies of non-patent IDS Cite Request for Corrected Filing Receipt Request for Correction of Recorded Assignment/Response: Amendment/Response: After Final Status Request Revocation and Substitute Power of Att	O/SB/08A ed Reference signment	Appeal Commun Interferences Appeal Commun (Appeal Notice, Certified Copy of After Allowance)	raftsperson s): s) of Figure(s) [ication to Boar lication to Grou Brief, Reply Bri f Priority Docum	d of Appe ip ief) nent(s)		nd .
Signature: June 1. Attorney/Reg. No.: John J. McNelis/Reg	No. 37,186 CERTIFIC De enclosures is ssioner for Pat then this dorre	ATE OF MAILING identified above, is being depositents, P.O. Box 1450, Alexandria	Dated:	d States P	te show	ervice as
Typed or Printed Name: John T. McNeli	s		Dated:	26 VI	an i	2004
Express Mail Mailing Number (optional):					>	

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ICANT:

Steven W. Meeks and Rusmin Kudinar

APPLICATION NO.:

10/782,267

FILING DATE:

February 18, 2004

TITLE:

System for Simultaneously Measuring Thin Film Layer Thickness,

Reflectivity, Roughness, Surface Profile and Magnetic Pattern

EXAMINER:

Not Yet Known

GROUP ART UNIT:

2877

ATTY. DKT. NO.:

20830-08855

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner For Patents, P.O. Box 1450, Alexandrid, VX 22317-1450, on the date shown below:

Dated:

By:

John T. McNelis, Reg. No.: 37,186

COMMISSIONER FOR PATENTS

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INFORMATION DISCLOSURE STATEMENT Under 37 CFR §§ 1.56 and 1.97-98

SIR:

Pursuant to the provisions of 37 CFR §§ 1.56 and 1.97-98, enclosed herewith is modified form PTO/SB/08A listing references for consideration by the Examiner. Enclosed is a copy of each listed non-patent reference that may be material to the examination of this application, and for which there may be a duty to disclose.

The filing of this Information Disclosure Statement shall not be construed as a representation regarding the completeness of the list of references, or that inclusion of a reference in this list is an admission that it is prior art or is pertinent to this application, or that a search has been made, or as an admission that the information listed is, or may be considered to be, material to patentability, or that no other material information exists, and shall not be construed as an admission against interest in any manner.

This Information Disclosure Statement is being filed:

 \boxtimes within three months of the filing date of the application, or date of entry into the national stage of an international application, or before the mailing date of a first office action on the merits, whichever event last occurred;

Ш			ining of a first official action after the firing of a request for
			amination (RCE) under 37 CFR § 1.114;
			onths of the filing date of this national application or the date
		•	e national stage in an international application, or after the
•		_	of the first official action on the merits, whichever event last
	occurr	ed, but	before the mailing date of the first to occur of either: (1) a
	final a	ction u	nder 37 CFR §1.113; or (2) an action that otherwise closes
	prosec	ution in	n the application, and:
		attac	hed hereto is the fee set forth under 37 CFR §1.17(p) for
		subm	nission of this Information Disclosure Statement under 37
		CFR	.§ 1.97(c); OR
		Appl	icant certifies pursuant to 37 CFR § 1.97(e) that:
		$\overline{}$	each item of information contained in this Information
			Disclosure Statement was first cited in a communication
			from a foreign patent office in a counterpart foreign
			application not more than three months prior to the filing of
			this Statement; OR
			no item of information contained in this Information
			Disclosure Statement was cited in a communication from a
			foreign patent office in a counterpart foreign application
			and, to the knowledge of the person signing this
			certification after making reasonable inquiry, no item of
			information contained in this Statement was known to any
			individual designated under 37 CFR § 1.56(c) more than
			three months prior to the filing of this Statement;
	on or	before	the payment of the issue fee but after the mailing date of the
	first t	o occur	of either: (1) a final action under 37 CFR § 1.113; (2) a
	notice	e of allo	owance under 37 CFR § 1.311; or (3) an action that otherwise
	closes	s prosec	cution in the application, and:
		Appl	icant certifies pursuant to 37 CFR. § 1.97(e) that:
			each item of information contained in this Information
			Disclosure Statement was cited in a communication from a
			foreign patent office in a counterpart foreign application not
			more than three months prior to the filing of this Statement;
			or
			no item of information contained in this Information
			Disclosure Statement was cited in a communication from a

					foreign patent office in a counterpart foreign application
					and, to the knowledge of the person signing this
					certification after making reasonable inquiry, no item of
					information contained in this Statement was known to any
					individual designated under 37 CFR § 1.56(c) more than
					three months prior to the filing of this Statement; AND
			П		d hereto is the fee set forth under 37 CFR §1.17(p) for
			_		sion of this Information Disclosure Statement under 37
•					1.97(c); OR
			after th	Ū	ent of the issue fee. Applicant requests that the information
					is Information Disclosure Statement be placed in the file
					7 CFR § 1.97(i), although the information may not be
				-	the USPTO.
					, under 35 U.S.C. § 120, on the earlier filing date of prior
•		_	-		ICATION NO., filed on DATE FILED, and the references
					y referenced, but are not required to be provided in this
					CFR § 1.98(d).
•	П				ion contained in this Information Disclosure Statement was
					ion from a foreign patent office in a counterpart application,
				•	n was not received by any individual designated in 37 CFR
					irty days prior to the filing of this Information Disclosure
					1.704(d).
	\boxtimes				t no fee is required for the consideration of this Information
		Disclos			
	Consid				Ferences and favorable action are solicited.
					Respectfully submitted,
					STEVEN W. MEEKS AND RUSMIN KUDINAR
			1		
Dated:	25	6 blay	2001		By: John f.
		,			John T. McNelis, Reg. No.: 37,186
					Fenwick & West LLP Silicon Valley Center
					801 California Street
					Mountain View, CA 94041
					Tel.: (650) 335-7133
					may '10311 U4X_3 /UII '

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ALS THE	Substitute for fo	orm 1449/	VPTO		Complete if Known	
INFO		חופי	CLOSURE	Application No.	10/782,267	
•			PPLICANT	Filing Date	February 18, 2004	
SIAI	CINICIAL) I Ar	PLICANI	First Named Inventor	Steven W. Meeks	
				Art Unit	2877	
				Examiner Name	Not Yet Known	
Sheet	1	of	4	Attorney Docket Number	20830-08855	

	U.S. PATENT DOCUMENTS								
•		Document No.							
Examiner Initials*	Cite No.1	Number – Kind Code ² (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document					
	A1	3,885,875	05/27/1975	Rosenfeld et al.					
	A2	4,332,477	06/01/1982	Sato					
	A3	4,585,348	04/29/1986	Chastang et al.					
	A4	4,668,860	05/26/1987	Anthon					
	A5	4,870,631	09/26/1989	Stoddard					
	A6	4,873,430	10/10/1989	Juliana et al.					
	A7	5,017,012	05/21/1991	Merritt, Jr. et al.					
	A8	5,129,724	07/14/1992	Brophy et al.					
	A9	5,189,481	02/23/1993	Jann et al.					
	A10	5,196,906	03/23/1993	Stover et al.					
	A11	5,270,794	12/14/1993	Tsuji et al.					
	A12	5,293,216	03/08/1994	Moslehi					
	A13	5,313,542	05/17/1994	Castonguay					
	A14	5,406,082	04/11/1995	Pearson et al.					
	A15	5,416,594	05/16/1995	Gross et al.					
	A16	5,446,549	08/29/1995	Mazumder et al.					
	A17	5,463,897	11/07/1995	Prater et al.					
	A18	5,608,527	03/04/1997	Valliant et al.					
	A19	5,610,897	03/11/1997	Yamamoto et al.					
	A20	5,633,747	05/27/1997	Nikoonahad					
	A21	5,644,562	07/01/1997	de Groot					
	A22	5,694,214	12/02/1997	Watanabe et al.					
	A23	5,726,455	03/10/1998	Vurens					
	A24	5,748,305	05/05/1998	Shimono et al.					
	A25	5,777,740	07/07/1998	Lacey et al.					
	A26	5,798,829	08/25/1998	Vaez-Iravani					
	A27	5,864,394	01/26/1999	Jordan, III et al.					
	A28	5,875,029	02/23/1999	Jann et al.					
	A29	5,880,838	03/09/1999	Marx et al.					
	A30	5,903,342	05/11/1999	Yatsugake et al.					

Examiner	 Date	
Signature	Considered	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609.

Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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	Substitute for f	orm 1449/	VPTO		Complete if Known	
INE	ORMATION	ו חופי	CLOSUDE	Application No.	10/782,267	
•	ATEMENT E			Filing Date	February 18, 2004	
31.	AIEWENIE	o i Ar	PLICANT	First Named Inventor	Steven W. Meeks	
				Art Unit	2877	
				Examiner Name	Not Yet Known	
Sheet	. 2	of	4	Attorney Docket Number	20830-08855	

	U.S. PATENT DOCUMENTS									
•		Document No.								
Examiner Initials*	Cite No.1	Number – Kind Code ² (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document						
	A31	5,951,891	09/14/1999	Barenboim et al.						
	A32	5,978,091	11/02/1999	Jann et al.						
	A33	5,985,680	11/16/1999	Singhal et al.						
	A34	5,986,761	11/16/1999	Crawforth et al.						
	A35	5,986,763	11/16/1999	Inoue						
	A36	5,995,226	11/30/1999	Abe et al.						
	A37	6,081,325	06/27/2000	Leslie et al.						
	A38	6,088,092	07/11/2000	Chen et al.						
	A39	6,091,493	07/18/2000	Stover et al.						
	A40	6,107,637	08/22/2000	Watanabe et al.						
•	A41	6,118,525	09/12/2000	Fossey et al.						
	A42	6,134,011	10/17/2000	Klein et al.						
•	A43	6,157,444	12/05/2000	Tomita et al.						
	A44	6,169,601	01/2001	Eremin et al.						
	A45	6,172,752	01/09/2001	Haruna et al.						
	A46	6,201,601B1	03/13/2001	Vaez-Iravani et al.						
	A47	6,248,988	06/19/2001	Krantz						
	A48	6,271,916B1	08/07/2001	Marxer et al.						
	A49	6,307,627	10/23/2001	Vurens						
	A50	6,353,222B1	03/05/2002	Dotan						
	A51	6,384,910B2	05/07/2002	Vaez-Iravani et al.						
	A52	6,509,966B2	01/21/2003	Ishiguro et al.						
	A53	6,542,248B1	04/01/2003	Schwarz						
	A54	6,603,542	08/202003	Chase et al.						
		ļ								
	<u> </u>		1							

Examiner Signature	Date Considered	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609.

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¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

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		Substitute for fo	orm 1449/	VPTO	Complete if Known			
11	VEO E		ו חופו	CLOSURE	Application No.	10/782,267		
•				PLICANT	Filing Date	February 18, 2004		
3	IAI		o i Ar	PLICANT	First Named Inventor	Steven W. Meeks		
					Art Unit	2877	•	
					Examiner Name	Not Yet Known		
Shee	t .	3	of	4	Attorney Docket Number	20830-08855		

		"	U.S. PATE	NT DOCUMENTS		
		Document No.				
Examiner Initials*	Cite No.1	Number – Kind Code ² (if known)	Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
•			FOREIGN PA	TENT DOCUMENTS		
		Foreign Patent Document				
Examiner Initials*	Cite No. ¹	Country Code ³ – Number ⁴ Kind Code ⁵ (if known)	Publication Date MM-DD- YYYY	Name of Patentee or Applicant of Cited Document	T ⁶	
	B1	WO 98/52019	11/19/1998	Technische Universiteit Delft		
	B2	JP 3-221804	09/30/1991	NEC Corp		

Examiner Signature	Date Considered	·

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¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁴Applicant is to place a check mark here if English language Translation is attached.

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Substitute for form 1449A/PTO			VPTO	Complete if Known		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application No.	10/782,267	
				Filing Date	February 18, 2004	
STATEMENT BY APPLICANT			PLICANI	First Named Inventor	Steven W. Meeks	4
,				Art Unit	2877	
				Examiner Name	Not Yet Known	
Sheet	. 4	of	4	Attorney Docket Number	20830-08855	

		OTHER REFERENCES - NON-PATENT LITERATURE DOCUMENTS	
Examiner initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ⁶
	C1	W.C. Leung, W. Crooks, H. Rosen and T. Strand, An Optical Method Using a Laser and an Integrating Sphere Combination for Characterizing the Thickness Profile of Magnetic Media, Sept. 1989, IEEE Transaction on Magnetics, Vol. 25, No. 5. Pages 3659-3661.	0
	C2	Steven W. Meeks, Walter E. Weresin, and Hal J. Rosen, <i>Optical Surface Analysis of the Head-Disk-Interface of Thin Film Disks</i> , January 1995, Transactions of the ASME, Journal of Tribology, Vol. 117, pages 112-118.	,
	C3	Steven Meeks, Maxtor and Rusmin Kudinar, <i>The Next Battleground: Head-Disk Interface</i> , March 1998, Data Storage, Test & Measurement, pages 29-30, 34 and 38.	
	C4	Laser Scanning Surface Profilometer, [online], August 1970, [retrieved January 29, 2001], Pages 789-790, Retrieved from the Internet: <url: http:="" tdb?&order="7OC101758.</td" tdbs="" www.delphion.com=""><td></td></url:>	
	C5	Meeks, Steven W.: "A Combined Ellipsometer, Reflectometer, Scatterometer and Kerr Effect Microscope for Thin Film Disk Characterization," Machine Vision Applications in Industrial Inspection VIII, Proceedings of SPIE, vol. 3966, 2000, pages 385-391, XP001085220.	

Examiner Signature	·	Date Considered	
	·		

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